

Notice of References Cited	Application/Control No. 10/705,887		Applicant(s)/Patent Under Reexamination WANG ET AL.	
	Examiner Prabodh M. Dharja		Art Unit 2629	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0227713 A1	11-2004	Sun, Wein Town	345/098
*	B	US-2004/0131279 A1	07-2004	Poor, David S	382/287
*	C	US-2002/0126106 A1	09-2002	NAITO, KEIJIRO	345/204
*	D	US-2002/0140711 A1	10-2002	Saito et al.	345/660
*	E	US-2005/0078101 A1	04-2005	Shigeta, Kazuyuki	345/204
*	F	US-6,710,809 B1	03-2004	Niikawa, Masahito	348/372
*	G	US-6,710,809 B1	03-2004	Niikawa, Masahito	348/372
*	H	US-6,160,532	12-2000	Kaburagi et al.	345/87
*	I	US-2002/0044126 A1	04-2002	Aoki, Toru	345/96
*	J	US-2003/0020678 A1	01-2003	Ozawa et al.	345/87
*	K	US-2005/0244054 A1	11-2005	Hsieh, Wen-Hsuan	382/167
*	L	US-2002/0005846 A1	01-2002	Hiroki et al.	345/204
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.